


<b>Search Notes</b> 	<b>Application/Control No.</b> 10666815	<b>Applicant(s)/Patent Under Reexamination</b> CHEN ET AL.
	<b>Examiner</b> Neway, Samuel G	<b>Art Unit</b> 2626

SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES		
Search Notes	Date	Examiner
EAST: Text Search, PLUS Search, Assignee Searc, Inventor Searchh	02/13/07	SN
Consulted: T. Smits, AU 2626	02/15/07	SN
Consulted: Todd Swann, WQAS, TC 2100: regarding 101 issues.	02/16/07	SN

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner